

<b>Notice of References Cited</b>	Application/Control No. 10/599,804	Applicant(s)/Patent Under Reexamination KANE ET AL.	
	Examiner DAVID WEISZ	Art Unit 1797	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yamamura et al. "Quantitative analysis of crystalline pharmaceuticals in powders and tablets by a pattern-fitting procedure using X-ray powder diffraction data". 2001. International Journal of Pharmaceutics. Vol 212, Pp 203-212.
	V	
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